

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Saito et al.

Confirmation No.: 5884

Serial No.: 10/561,280

Group Art Unit: 2877

Filing Date: 06/18/2004

Title: Optical Waveform Measurement Device and Measurement Method Thereof, Complex Refractive Index Measurement Device and Measurement Method Thereof, and Computer Program Recording Medium Containing the Program

To: Commissioner for Patents  
Alexandria VA 22313

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to applicant's duty of disclosure as set forth in 37 C.F.R. 1.56, applicant submits herewith on PTO-Form 1449, a list of references with copies enclosed herewith. References for No 3 and 4 are in Japanese and no translations are available to applicant. An English language copy of the International Search Report for a corresponding PCT application is included to satisfy the requirement for a statement of relevance.

This Supplemental Information Disclosure Statement is being submitted within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set

Docket No.: 1215.003

forth in 37 CFR 1.491 in an international application; before the mailing date of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114. No fee under 37 CFR 1.17 (p) is therefore required.

It is respectfully requested that this art be considered by the Examiner in the above identified application and made of record therein.

Respectfully submitted,



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Dated: June 13, 2008

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